

**Search Notes**

Application/Control No.

10/816,230

Examiner

Christopher L. Chin

Applicant(s)/Patent under  
Reexamination

BLATT ET AL.

Art Unit

1641

**SEARCHED**

Class	Subclass	Date	Examiner
422	55	6/26/2005	CC
422	56		
422	57		
422	58		
435	287.1		
435	287.2		
435	287.7		
435	287.8		
435	287.9		
435	288.5		
435	805		
435	810		
435	970		
435	973	6/26/2005	CC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Checked parent cases	6/26/2005	CC

**Search Notes (continued)**

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**SEARCHED**

Class	Subclass	Date	Examiner
436	169	6/26/2005	CC
436	514		
436	518		
436	530		
436	810	6/26/2005	CC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR